

MIL-STD-883E

METHOD 1006

INTERMITTENT LIFE

1. PURPOSE. The intermittent life test is performed for the purpose of determining a representative failure rate for microelectronic devices or demonstrating quality or reliability of devices subjected to the specified conditions. It is intended for applications where the devices are exposed to cyclic variations in electrical stresses between the "on" and "off" condition and resultant cyclic variations in device and case temperatures.

2. APPARATUS. See method 1005 of this standard.

3. PROCEDURE. The device shall be tested in accordance with all the requirements of method 1005 except that all electrical stresses shall be alternately applied and removed. The "on" and "off" periods shall be initiated by sudden, not gradual, application or removal of the specified electrical inputs (including signal and bias).

4. SUMMARY. In addition to the requirements of method 1005 of this standard, the following detail shall be specified in the applicable acquisition document:

Frequency and duration of "on" and "off" cycles.